ALPHA & OMEGA SEMICONDUCTOR

Green Product RoHS Compliant

AOD609G
Complementary Enhancement Mode Field Effect Transistor

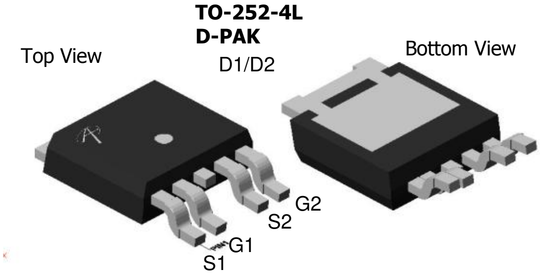
General Description

The AOD609G uses advanced trench technology MOSFETs to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs may be used in H-bridge, Inverters and other applications.

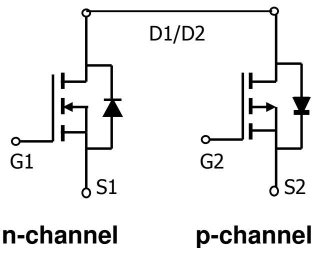
-RoHS Compliant
-Halogen Free*

Features

n-channel
V_{DS} (V) = 40V, I_D = 12A (V_{GS}=10V)
$R_{DS(ON)}$< 30mΩ (V_{GS}=10V)
$R_{DS(ON)}$< 40mΩ (V_{GS}=4.5V)
p-channel
V_{DS} (V) = -40V, I_D = -12A (V_{GS}=-10V)
$R_{DS(ON)}$< 45mΩ (VGS= -10V)
$R_{DS(ON)}$< 66mΩ (VGS= -4.5V)
100% UIS Tested!
100% Rg Tested!



Top View
Drain Connected
to Tab



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage		V_{DS}	40	-40	V
Gate-Source Voltage		V_{GS}	±20	±20	V
Continuous Drain Current [B,H]	T_C=25°C	I_D	12	-12	A
	T_C=100°C		12	-12	
Pulsed Drain Current [B]		I_{DM}	30	-30	
Avalanche Current [C]		I_{AR}	14	-20	
Repetitive avalanche energy L=0.1mH [C]		E_{AR}	9.8	20	mJ
Power Dissipation	T_C=25°C	P_D	27	30	W
	T_C=100°C		14	15	
Power Dissipation	T_A=25°C	P_{DSM}	2	2	W
	T_A=70°C		1.3	1.3	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 175	-55 to 175	°C

Thermal Characteristics: n-channel and p-channel

Parameter		Symbol	Device	Typ	Max	Units
Maximum Junction-to-Ambient [A,D]	t ≤ 10s	$R_{\theta JA}$	n-ch	17.4	25	°C/W
Maximum Junction-to-Ambient [A,D]	Steady-State		n-ch	50	60	°C/W
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JC}$	n-ch	4	5.5	°C/W
Maximum Junction-to-Ambient [A,D]	t ≤ 10s	$R_{\theta JA}$	p-ch	16.7	25	°C/W
Maximum Junction-to-Ambient [A,D]	Steady-State		p-ch	50	60	°C/W
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JC}$	p-ch	3.5	5	°C/W

N Channel Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	40			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=40V, V_{GS}=0V			1	µA
		T_J=55°C			5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±20V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	1.7	2.5	3	V
$I_{D(ON)}$	On state drain current	V_{GS}=10V, V_{DS}=5V	30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=12A		24	30	mΩ
		T_J=125°C		37	46	
		V_{GS}=4.5V, I_D=8A		31	40	
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=12A		25		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.76	1	V
I_S	Maximum Body-Diode Continuous Current				2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=20V, f=1MHz		545		pF
C_{oss}	Output Capacitance			65		pF
C_{rss}	Reverse Transfer Capacitance			40		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	1.6	3.2	4.8	Ω
SWITCHING PARAMETERS						
Q_g (10V)	Total Gate Charge	V_{GS}=10V, V_{DS}=20V, I_D=12A		10	13	nC
Q_{gs}	Gate Source Charge			2		nC
Q_{gd}	Gate Drain Charge			2.2		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=20V, R_L=1.4Ω, R_{GEN}=3Ω		5.5		ns
t_r	Turn-On Rise Time			3		ns
$t_{D(off)}$	Turn-Off DelayTime			19		ns
t_f	Turn-Off Fall Time			4		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=12A, dI/dt=100A/µs		13		ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=12A, dI/dt=100A/µs		6.5		nC

A: The value of $R_{\theta JA}$ is measured with the device in a still air environment with T_A =25° C. The power dissipation P_{DSM} and current rating I_{DSM} are based on $T_{J(MAX)}$=150° C, using the steady state junction-to-ambient thermal resistance.
B. The power dissipation P_D is based on $T_{J(MAX)}$=175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
C: Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=175° C.
D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to case $R_{\theta JC}$ and case to ambient.
E. The static characteristics in Figures 1 to 6 are obtained using <300 µs pulses, duty cycle 0.5% max.
F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$=175° C. The SOA curve provides a single pulse rating.
G. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.
H. The maximum current rating is limited by bond-wires.
*This device is guaranteed green after data code 8X11 (Sep 1ST 2008).
Rev4: Aug 2009

P-Channel Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Typ	Max	Units
STATIC PARAMETERS							
BV_{DSS}	Drain-Source Breakdown Voltage	I_D= -250µA, V_{GS}=0V		-40			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}= -40V, V_{GS}=0V				-1	µA
			T_J=55°C			-5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D= -250µA		-1.7	-2	-3	V
$I_{D(ON)}$	On state drain current	V_{GS}= -10V, V_{DS}= -5V		-30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}= -10V, I_D= -12A			36	45	mΩ
			T_J=125°C		52	65	
		V_{GS}= -4.5V, I_D= -8A			51	66	
g_{FS}	Forward Transconductance	V_{DS}= -5V, I_D= -12A			22		S
V_{SD}	Diode Forward Voltage	I_S= -1A,V_{GS}=0V			-0.76	-1	V
I_S	Maximum Body-Diode Continuous Current					-2	A
DYNAMIC PARAMETERS							
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}= -20V, f=1MHz			890		pF
C_{oss}	Output Capacitance				90		pF
C_{rss}	Reverse Transfer Capacitance				60		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz		6.5	13	19.5	Ω
SWITCHING PARAMETERS							
Q_g (-10V)	Total Gate Charge	V_{GS}= -10V, V_{DS}= -20V, I_D= -12A			15.5	21	nC
Q_g (-4.5V)	Total Gate Charge				7	9	nC
Q_{gs}	Gate Source Charge				3.2		nC
Q_{gd}	Gate Drain Charge				3.5		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}= -10V, V_{DS}= -20V, R_L=1.4Ω, R_{GEN}=3Ω			10		ns
t_r	Turn-On Rise Time				15.5		ns
$t_{D(off)}$	Turn-Off DelayTime				35		ns
t_f	Turn-Off Fall Time				50		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F= -12A, dI/dt=100A/µs			20		ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F= -12A, dI/dt=100A/µs			11		nC

A: The value of $R_{\theta JA}$ is measured with the device in a still air environment with T_A =25°C. The power dissipation P_{DSM} and current rating I_{DSM} are based on $T_{J(MAX)}$=150°C, using t ≤ 10s junction-to-ambient thermal resistance.
B. The power dissipation P_D is based on $T_{J(MAX)}$=175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
C: Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=175°C.
D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to case $R_{\theta JC}$ and case to ambient.
E. The static characteristics in Figures 1 to 6 are obtained using <300 µs pulses, duty cycle 0.5% max.
F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$=175°C. The SOA curve provides a single pulse rating.
G. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C.
H. The maximum current rating is limited by bond-wires.
*This device is guaranteed green after data code 8X11 (Sep 1ST 2008).
Rev4: Aug 2009

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL

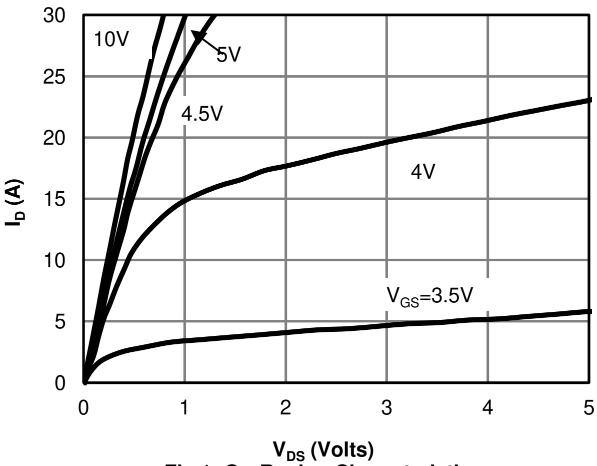


Fig 1: On-Region Characteristics

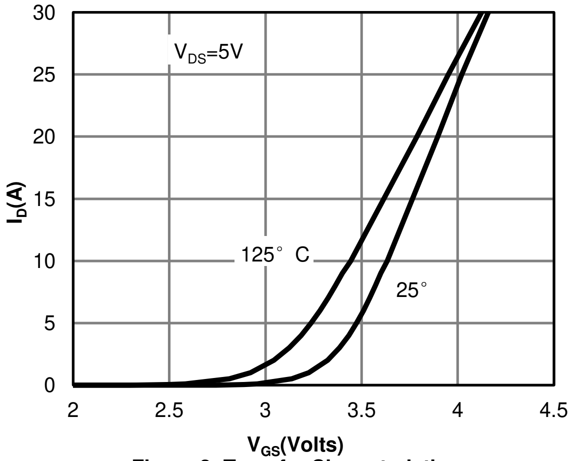


Figure 2: Transfer Characteristics

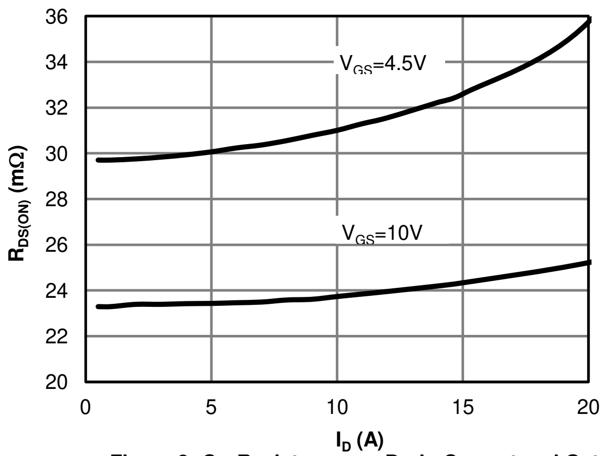


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

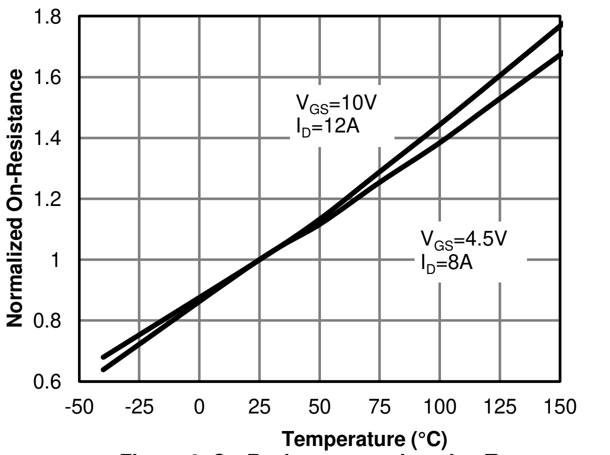


Figure 4: On-Resistance vs. Junction Temperature

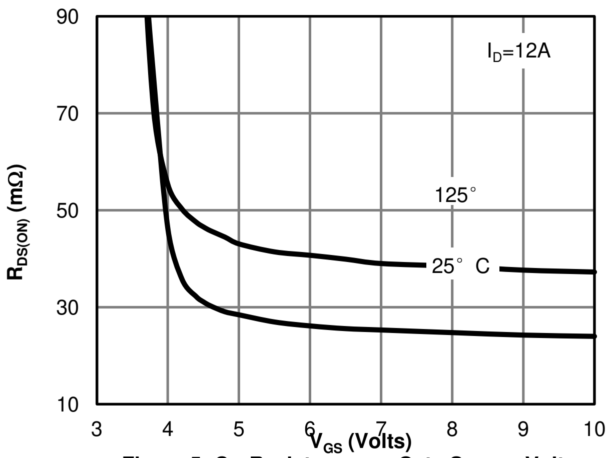


Figure 5: On-Resistance vs. Gate-Source Voltage

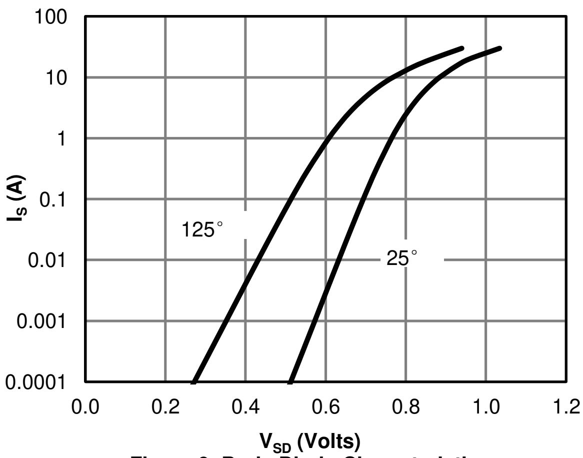


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL

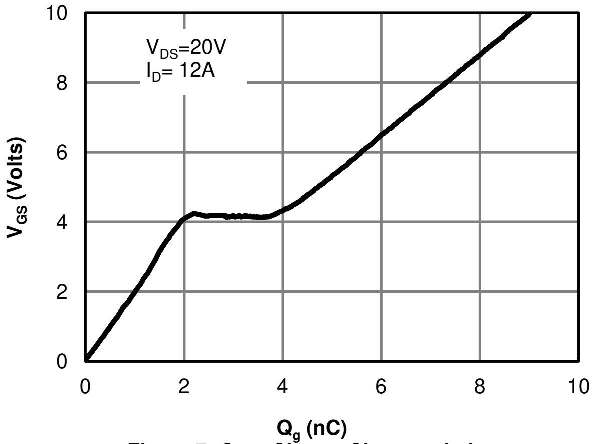


Figure 7: Gate-Charge Characteristics

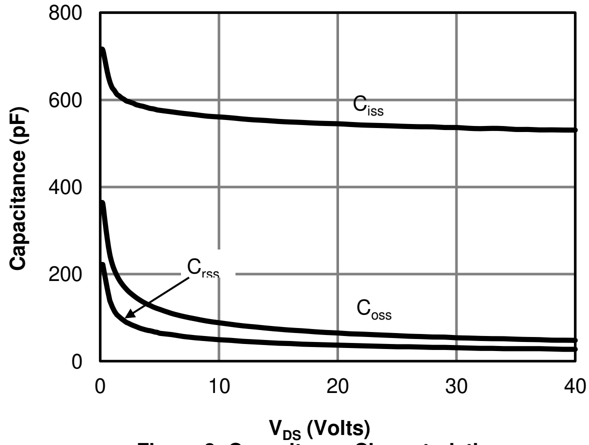


Figure 8: Capacitance Characteristics

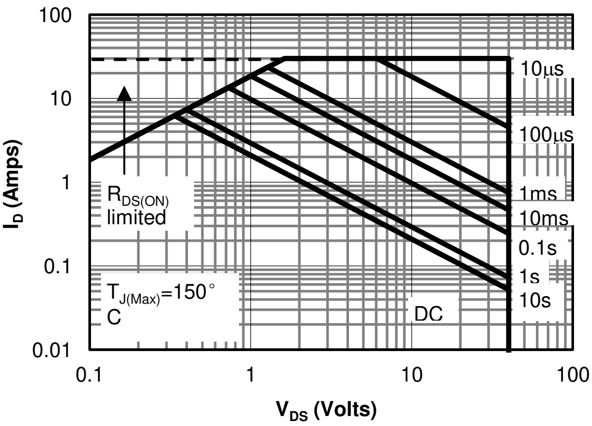


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

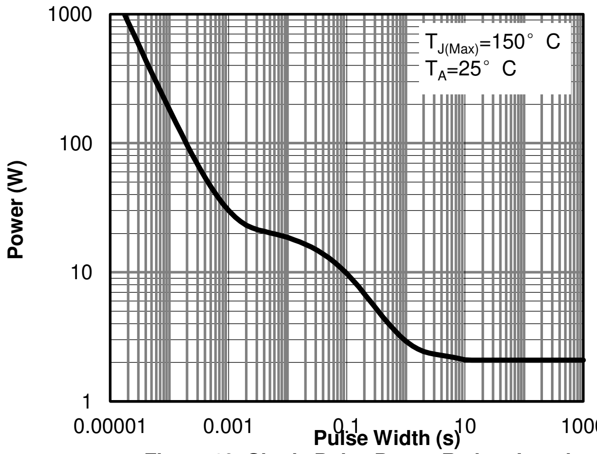


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

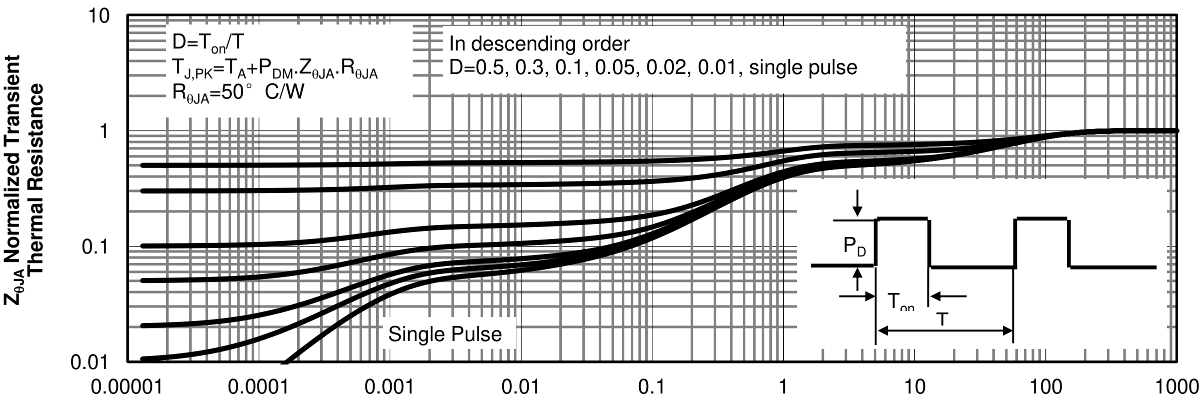


Figure 11: Normalized Maximum Transient Thermal Impedance

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

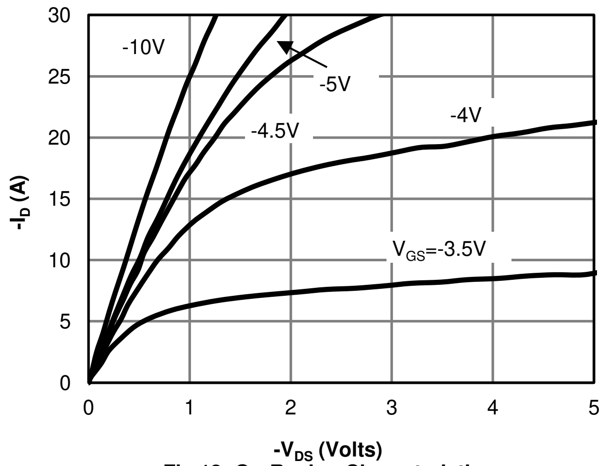


Fig 12: On-Region Characteristics

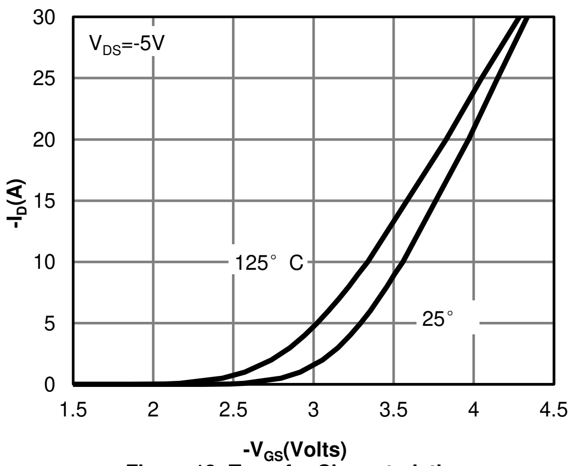


Figure 13: Transfer Characteristics

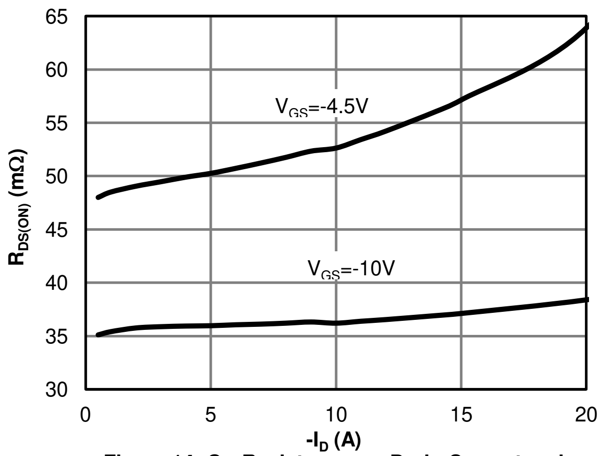


Figure 14: On-Resistance vs. Drain Current and Gate Voltage

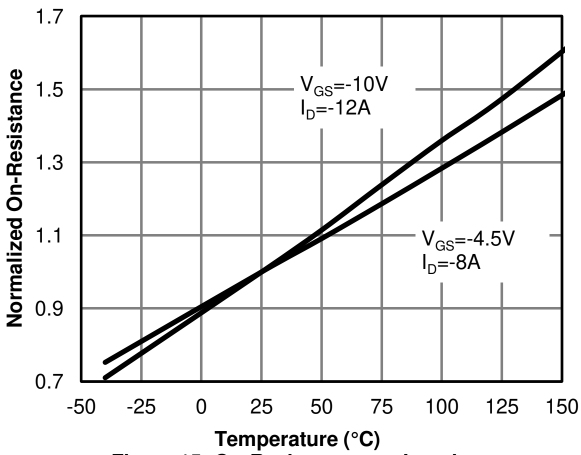


Figure 15: On-Resistance vs. Junction Temperature

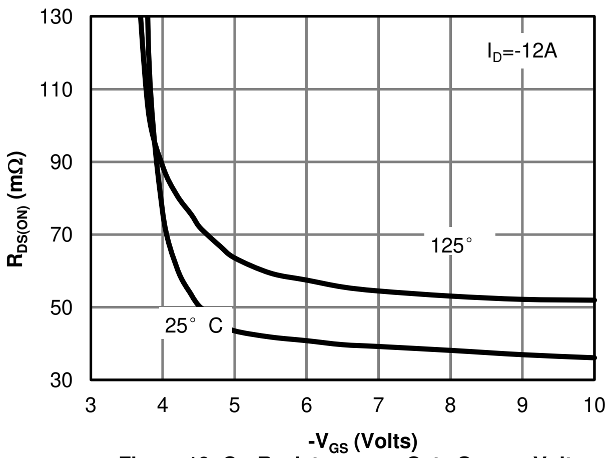


Figure 16: On-Resistance vs. Gate-Source Voltage

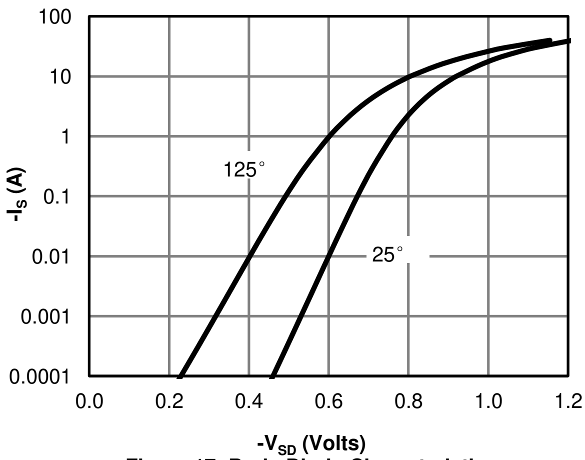


Figure 17: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

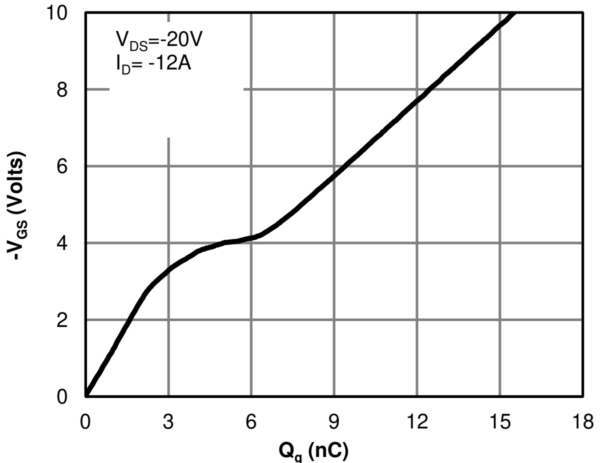


Figure 18: Gate-Charge Characteristics

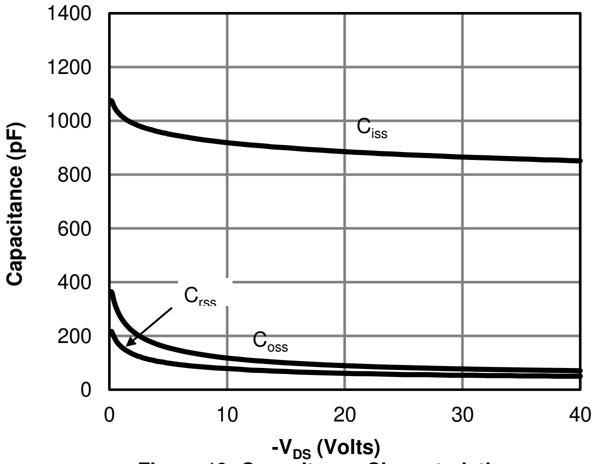


Figure 19: Capacitance Characteristics

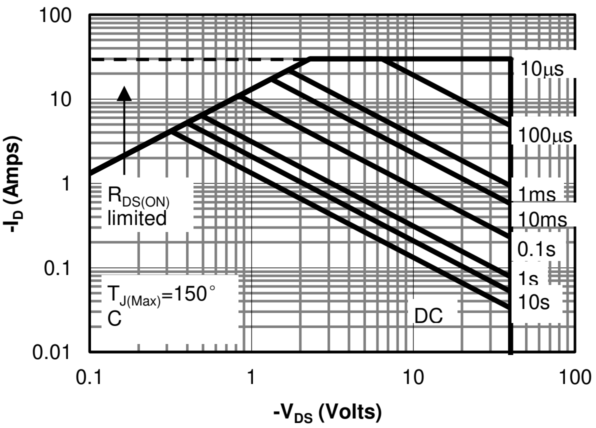


Figure 20: Maximum Forward Biased Safe Operating Area (Note E)

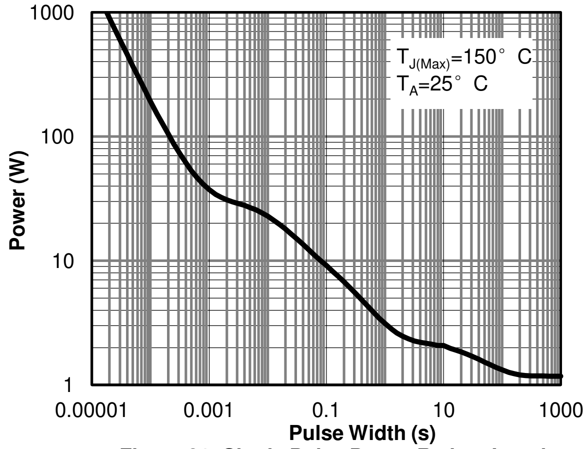


Figure 21: Single Pulse Power Rating Junction-to-Ambient (Note E)

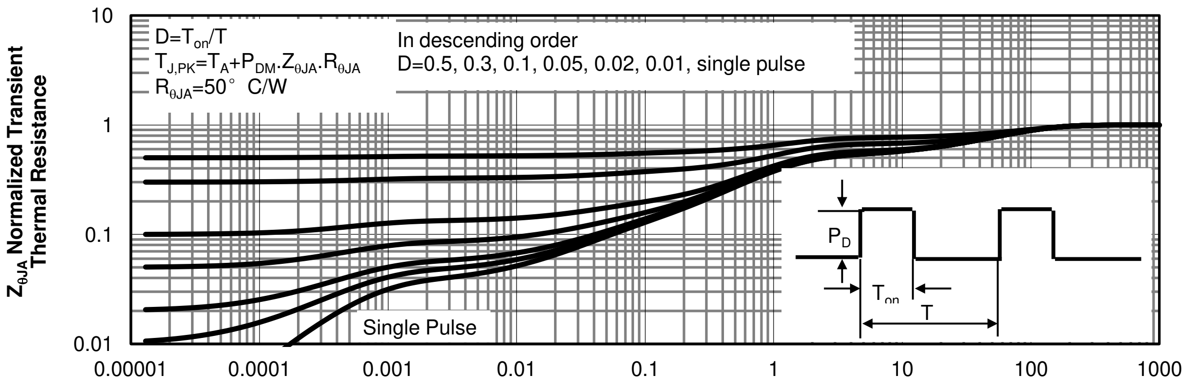
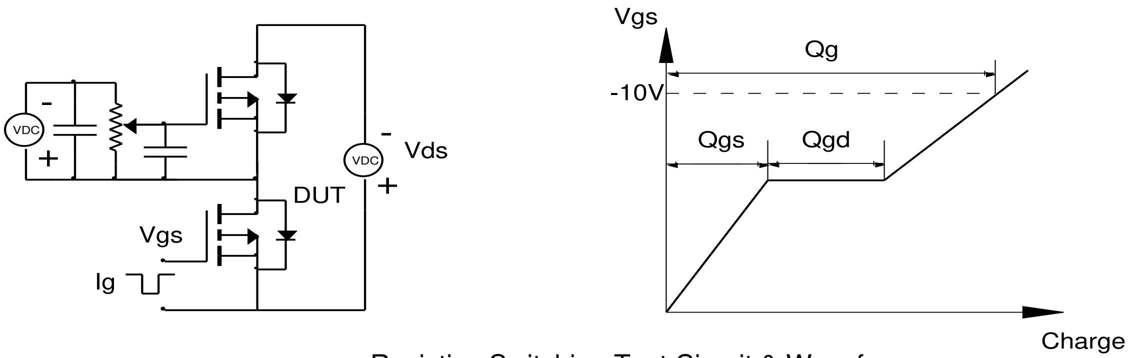
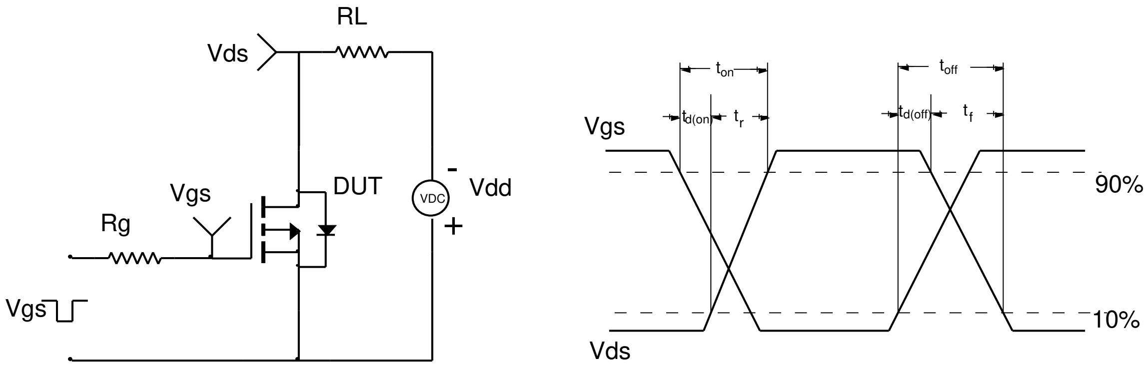


Figure 22: Normalized Maximum Transient Thermal Impedance

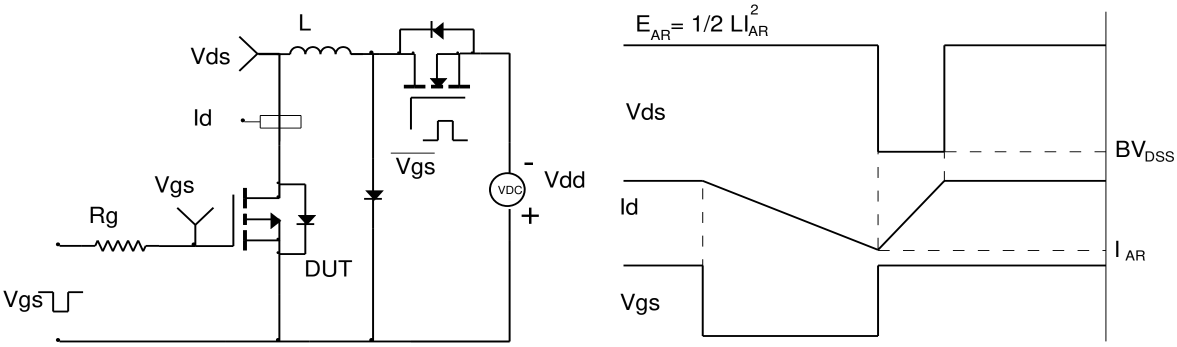
Gate Charge Test Circuit & Waveform



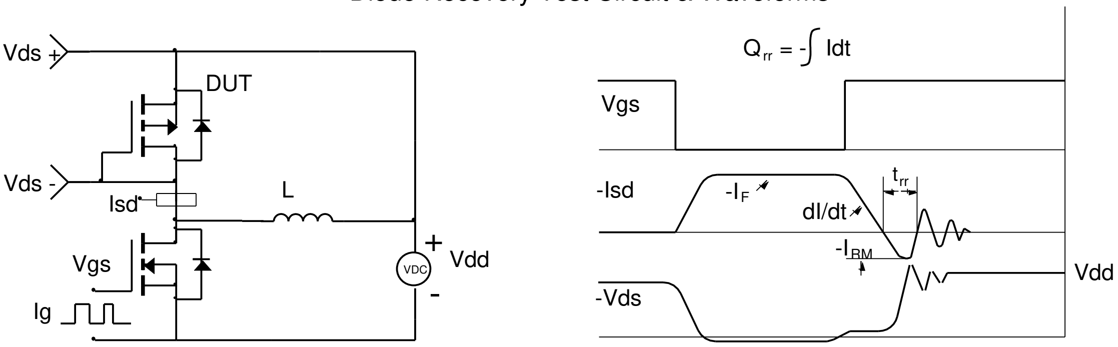
Resistive Switching Test Circuit & Waveforms



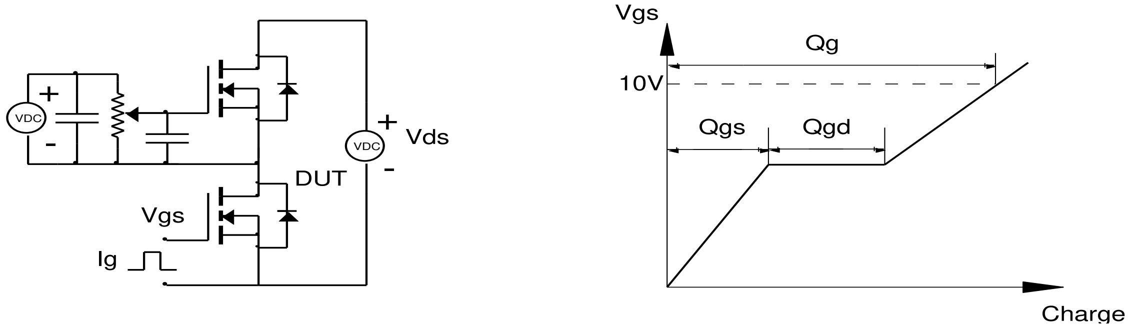
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



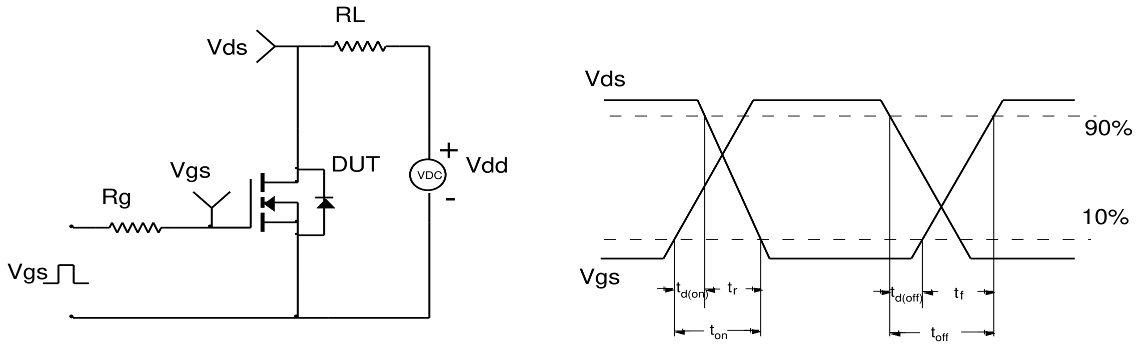
Diode Recovery Test Circuit & Waveforms



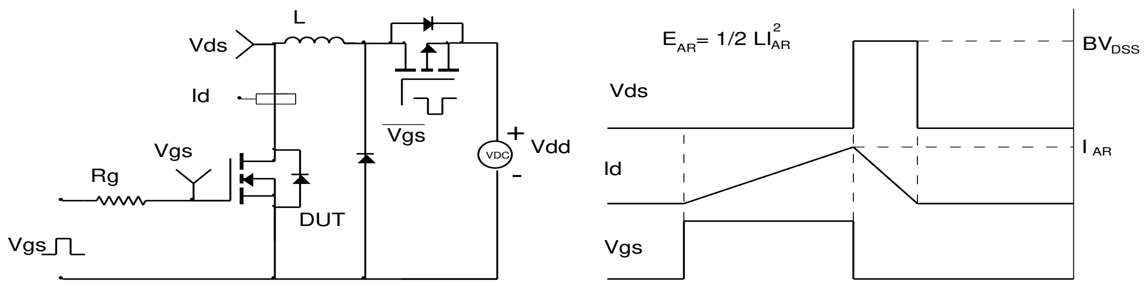
Gate Charge Test Circuit & Waveform



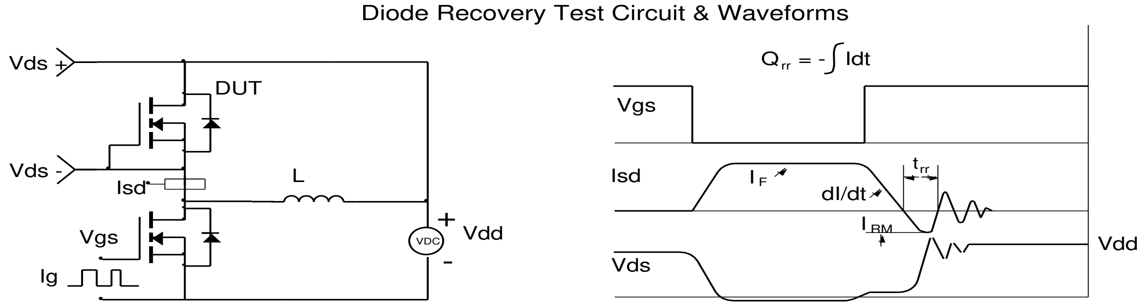
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



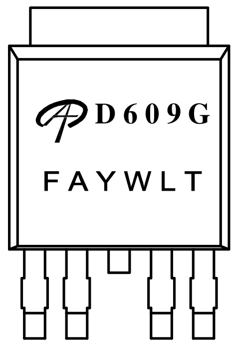
Diode Recovery Test Circuit & Waveforms



ALPHA & OMEGA
SEMICONDUCTOR

Document No.	PD-02982
Version	A
Title	AOD609G Marking Description

TO252-4L PACKAGE MARKING DESCRIPTION



Green product

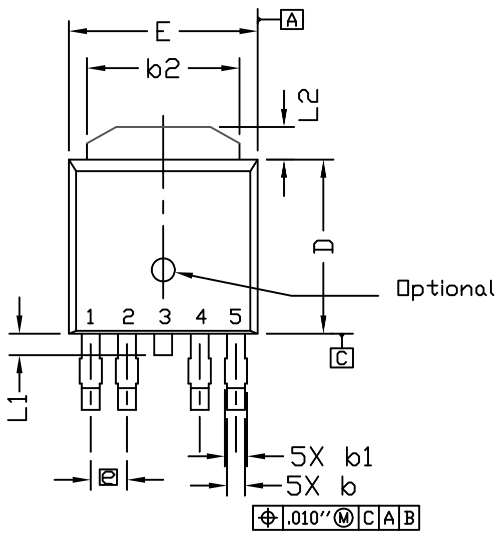
NOTE:
LOGO - AOS Logo
D609G - Part number code
F - Fab code
A - Assembly location code
Y - Year code
W - Week code
L&T - Assembly lot code

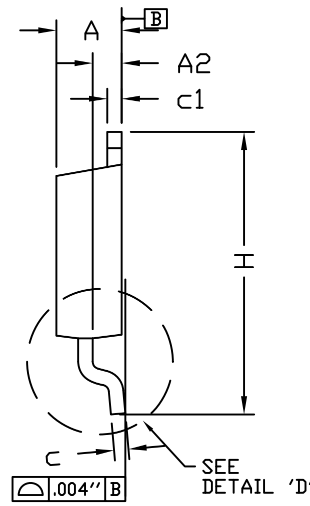
PART NO.	DESCRIPTION	CODE
AOD609G	Green product	D609G

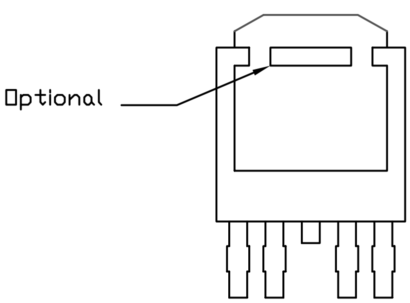
ALPHA & OMEGA
SEMICONDUCTOR, LTD.

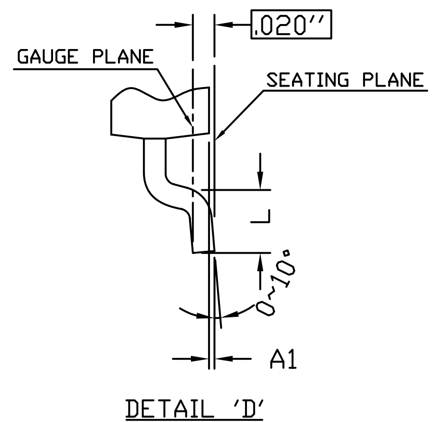
Document No.	PO-00033
Version	rev E

TO252_4L PACKAGE OUTLINE

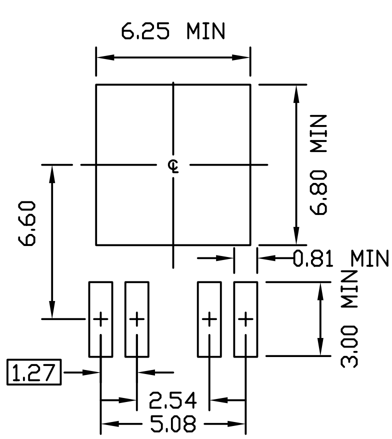








RECOMMENDED LAND PATTERN



UNIT: mm

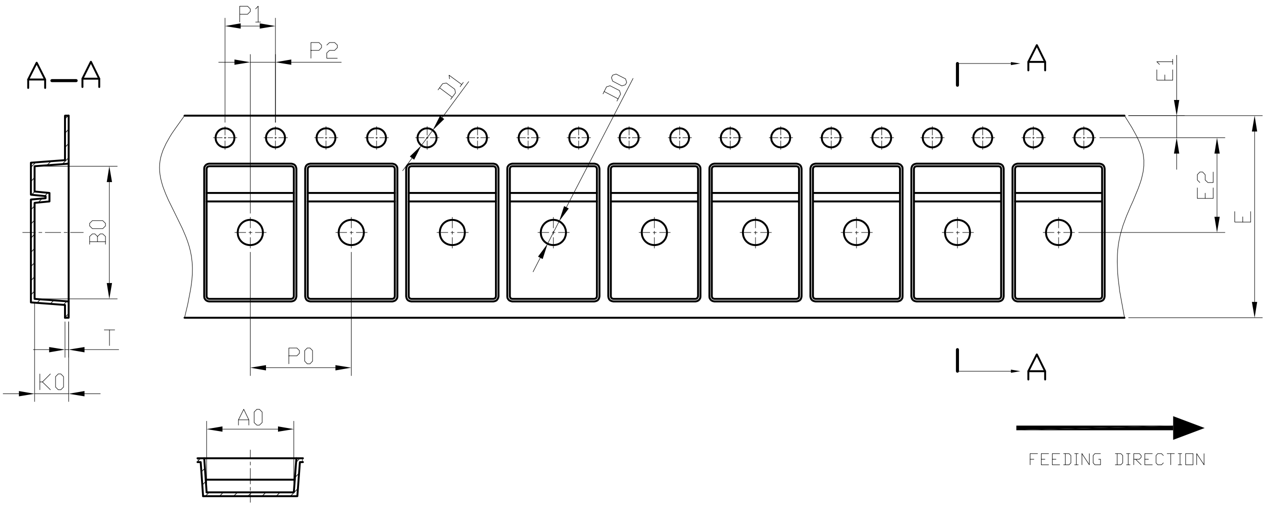
SYMBOL	DIMENSION IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	2.184	2.286	2.388	0.086	0.090	0.094
A1	0.000	-----	0.127	0.000	-----	0.005
A2	0.889	-----	1.143	0.035	-----	0.045
b	0.508	-----	0.711	0.020	-----	0.028
b1	0.584	-----	0.787	0.023	-----	0.031
b2	4.953	-----	5.461	0.195	-----	0.215
c	0.457	0.508	0.610	0.018	0.020	0.024
c1	0.457	-----	0.610	0.018	-----	0.024
D	5.969	6.096	6.223	0.235	0.240	0.245
E	6.350	6.604	6.731	0.250	0.260	0.265
e		1.270 BSC.			0.050 BSC.	
H	9.398	-----	10.414	0.370	-----	0.410
L	1.270	-----	2.032	0.050	-----	0.080
L1	-----	-----	1.016	-----	-----	0.040
L2	0.889	-----	1.270	0.035	-----	0.050

NOTE
1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH SHOULD BE LESS THAN 6 MIL.
2. DIMENSION L IS MEASURED IN GAUGE PLANE.
3. TOLERANCE 0.10 mm UNLESS OTHERWISE SPECIFIED.
4. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.
5. REFER TO JEDEC TO-252 (AD).

ALPHA & OMEGA SEMICONDUCTOR

TO-252-4L Tape and Reel Data

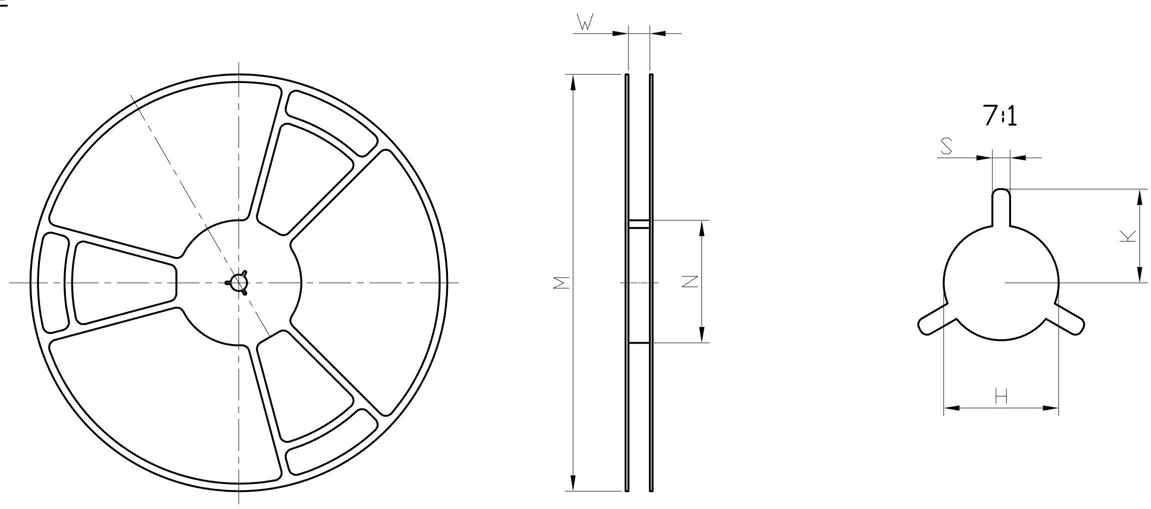
TO-252-4L Carrier Tape



UNIT: MM

PACKAGE	A0	B0	K0	D0	D1	E	E1	E2	P0	P1	P2	T
TO-252-4L (16 mm)	6.90 ±0.10	10.50 ±0.10	2.70 ±0.10	2.00 ±0.25	1.50 +0.1 −0	16.00 ±0.30	1.75 ±0.10	7.50 ±0.10	8.00 ±0.10	4.00 ±0.10	2.00 ±0.10	0.30 ±0.05

TO-252-4L Reel



UNIT: MM

TAPE SIZE	REEL SIZE	M	N	W	H	K	S
16 mm	ø330	ø330.00 ±0.5	ø97.00 ±1.0	17.0 +1.5 −0	ø13.00 +0.50 −0.20	10.6 ±0.25	2.0 ±0.5

TO-252-4L Tape

Leader / Trailer & Orientation

Unit Per Reel: 2500pcs